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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Obsolete
Core Processor	C166SV2
Core Size	16/32-Bit
Speed	80MHz
Connectivity	CANbus, EBI/EMI, I ² C, LINbus, SPI, SSC, UART/USART, USI
Peripherals	I ² S, POR, PWM, WDT
Number of I/O	118
Program Memory Size	448KB (448K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	50K x 8
Voltage - Supply (Vcc/Vdd)	3V ~ 5.5V
Data Converters	A/D 16x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	144-LQFP Exposed Pad
Supplier Device Package	PG-LQFP-144-4
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/xc2285m56f80laafxuma1

General Device Information

Table 6 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
8	P7.0	O0 / I	St/B	Bit 0 of Port 7, General Purpose Input/Output
	T3OUT	O1	St/B	GPT12E Timer T3 Toggle Latch Output
	T6OUT	O2	St/B	GPT12E Timer T6 Toggle Latch Output
	TDO_A	OH / IH	St/B	JTAG Test Data Output / DAP1 Input/Output If DAP pos. 0 or 2 is selected during start-up, an internal pull-down device will hold this pin low when nothing is driving it.
	ESR2_1	I	St/B	ESR2 Trigger Input 1
	RxDC4B	I	St/B	CAN Node 4 Receive Data Input
9	P7.3	O0 / I	St/B	Bit 3 of Port 7, General Purpose Input/Output
	EMUX1	O1	St/B	External Analog MUX Control Output 1 (ADC1)
	U0C1_DOUT	O2	St/B	USIC0 Channel 1 Shift Data Output
	U0C0_DOUT	O3	St/B	USIC0 Channel 0 Shift Data Output
	CCU62_CCP OS1A	I	St/B	CCU62 Position Input 1
	TMS_C	IH	St/B	JTAG Test Mode Selection Input If JTAG pos. C is selected during start-up, an internal pull-up device will hold this pin low when nothing is driving it.
	U0C1_DX0F	I	St/B	USIC0 Channel 1 Shift Data Input
10	P8.2	O0 / I	St/B	Bit 2 of Port 8, General Purpose Input/Output
	CCU60_CC6 2	O1	St/B	CCU60 Channel 2 Output
	TxDC1	O2	St/B	CAN Node 1 Transmit Data Output
	U1C1_DOUT	O3	St/B	USIC1 Channel 1 Shift Data output
	CCU60_CC6 2INB	I	St/B	CCU60 Channel 2 Input
11	P7.1	O0 / I	St/B	Bit 1 of Port 7, General Purpose Input/Output
	EXTCLK	O1	St/B	Programmable Clock Signal Output
	TXDC4	O2	St/B	CAN Node 4 Transmit Data Output
	CCU62_CTR APA	I	St/B	CCU62 Emergency Trap Input
	BRKIN_C	I	St/B	OCDS Break Signal Input

Table 6 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
39	P5.4	I	In/A	Bit 4 of Port 5, General Purpose Input
	ADC0_CH4	I	In/A	Analog Input Channel 4 for ADC0
	CCU63_T12 HRB	I	In/A	External Run Control Input for T12 of CCU63
	T3EUDA	I	In/A	GPT12E Timer T3 External Up/Down Control Input
	TMS_A	I	In/A	JTAG Test Mode Selection Input
40	P5.5	I	In/A	Bit 5 of Port 5, General Purpose Input
	ADC0_CH5	I	In/A	Analog Input Channel 5 for ADC0
	CCU60_T12 HRB	I	In/A	External Run Control Input for T12 of CCU60
41	P5.6	I	In/A	Bit 6 of Port 5, General Purpose Input
	ADC0_CH6	I	In/A	Analog Input Channel 6 for ADC0
42	P5.7	I	In/A	Bit 7 of Port 5, General Purpose Input
	ADC0_CH7	I	In/A	Analog Input Channel 7 for ADC0
43	P5.8	I	In/A	Bit 8 of Port 5, General Purpose Input
	ADC0_CH8	I	In/A	Analog Input Channel 8 for ADC0
	ADC1_CH8	I	In/A	Analog Input Channel 8 for ADC1
	CCU6x_T12H RC	I	In/A	External Run Control Input for T12 of CCU60/1/2/3
	CCU6x_T13H RC	I	In/A	External Run Control Input for T13 of CCU60/1/2/3
	U2C0_DX0F	I	In/A	USIC2 Channel 0 Shift Data Input
44	P5.9	I	In/A	Bit 9 of Port 5, General Purpose Input
	ADC0_CH9	I	In/A	Analog Input Channel 9 for ADC0
	ADC1_CH9	I	In/A	Analog Input Channel 9 for ADC1
	CC2_T7IN	I	In/A	CAPCOM2 Timer T7 Count Input

General Device Information

Table 6 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
56	P2.1	O0 / I	St/B	Bit 1 of Port 2, General Purpose Input/Output
	TxDC0	O1	St/B	CAN Node 0 Transmit Data Output
	CCU63_CC6 1	O2	St/B	CCU63 Channel 1 Output
	AD14	OH / IH	St/B	External Bus Interface Address/Data Line 14
	RxDC5C	I	St/B	CAN Node 5 Receive Data Input
	CCU63_CC6 1INB	I	St/B	CCU63 Channel 1 Input
	T5EUDB	I	St/B	GPT12E Timer T5 External Up/Down Control Input
	ESR1_5	I	St/B	ESR1 Trigger Input 5
57	P11.4	O0 / I	St/B	Bit 4 of Port 11, General Purpose Input/Output
	CCU61_CC6 2	O1	St/B	CCU61 Channel 2 Output
	U3C1_DOUT	O2	St/B	USIC3 Channel 1 Shift Data Output
	RxDC5B	I	St/B	CAN Node 5 Receive Data Input
	CCU61_CC6 2INB	I	St/B	CCU61 Channel 2 Input
	U3C1_DX0B	I	St/B	USIC3 Channel 1 Shift Data Input
58	P2.2	O0 / I	St/B	Bit 2 of Port 2, General Purpose Input/Output
	TxDC1	O1	St/B	CAN Node 1 Transmit Data Output
	CCU63_CC6 2	O2	St/B	CCU63 Channel 2 Output
	AD15	OH / IH	St/B	External Bus Interface Address/Data Line 15
	CCU63_CC6 2INB	I	St/B	CCU63 Channel 2 Input
	ESR2_5	I	St/B	ESR2 Trigger Input 5

Table 6 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
101	P3.5	O0 / I	St/B	Bit 5 of Port 3, General Purpose Input/Output
	U2C1_SCLK OUT	O1	St/B	USIC2 Channel 1 Shift Clock Output
	U2C0_SELO 2	O2	St/B	USIC2 Channel 0 Select/Control 2 Output
	U0C0_SELO 5	O3	St/B	USIC0 Channel 0 Select/Control 5 Output
	U2C1_DX1A	I	St/B	USIC2 Channel 1 Shift Clock Input
102	P0.6	O0 / I	St/B	Bit 6 of Port 0, General Purpose Input/Output
	U1C1_DOUT	O1	St/B	USIC1 Channel 1 Shift Data Output
	TxDC1	O2	St/B	CAN Node 1 Transmit Data Output
	CCU61_COU T63	O3	St/B	CCU61 Channel 3 Output
	A6	OH	St/B	External Bus Interface Address Line 6
	U1C1_DX0A	I	St/B	USIC1 Channel 1 Shift Data Input
	CCU61_CTR APA	I	St/B	CCU61 Emergency Trap Input
	U1C1_DX1B	I	St/B	USIC1 Channel 1 Shift Clock Input
103	P10.6	O0 / I	St/B	Bit 6 of Port 10, General Purpose Input/Output
	U0C0_DOUT	O1	St/B	USIC0 Channel 0 Shift Data Output
	TxDC4	O2	St/B	CAN Node 4 Transmit Data Output
	U1C0_SELO 0	O3	St/B	USIC1 Channel 0 Select/Control 0 Output
	AD6	OH / IH	St/B	External Bus Interface Address/Data Line 6
	U0C0_DX0C	I	St/B	USIC0 Channel 0 Shift Data Input
	U1C0_DX2D	I	St/B	USIC1 Channel 0 Shift Control Input
	CCU60_CTR APA	I	St/B	CCU60 Emergency Trap Input

General Device Information

Table 6 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
107	P3.7	O0 / I	St/B	Bit 7 of Port 3, General Purpose Input/Output
	U2C1_DOUT	O1	St/B	USIC2 Channel 1 Shift Data Output
	U2C0_SELO 3	O2	St/B	USIC2 Channel 0 Select/Control 3 Output
	U0C0_SELO 7	O3	St/B	USIC0 Channel 0 Select/Control 7 Output
	U2C1_DX0B	I	St/B	USIC2 Channel 1 Shift Data Input
111	P1.0	O0 / I	St/B	Bit 0 of Port 1, General Purpose Input/Output
	U1C0_MCLK OUT	O1	St/B	USIC1 Channel 0 Master Clock Output
	U1C0_SELO 4	O2	St/B	USIC1 Channel 0 Select/Control 4 Output
	A8	OH	St/B	External Bus Interface Address Line 8
	ESR1_3	I	St/B	ESR1 Trigger Input 3
	CCU62_CTR APB	I	St/B	CCU62 Emergency Trap Input
	T6INB	I	St/B	GPT12E Timer T6 Count/Gate Input
112	P9.0	O0 / I	St/B	Bit 0 of Port 9, General Purpose Input/Output
	CCU63_CC6 0	O1	St/B	CCU63 Channel 0 Output
	CCU63_CC6 0INA	I	St/B	CCU63 Channel 0 Input
	T6EUDB	I	St/B	GPT12E Timer T6 External Up/Down Control Input

Table 6 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
126	P9.5	O0 / I	St/B	Bit 5 of Port 9, General Purpose Input/Output
	CCU63_COU T62	O1	St/B	CCU63 Channel 2 Output
	U2C0_DOUT	O2	St/B	USIC2 Channel 0 Shift Data Output
	CCU62_COU T62	O3	St/B	CCU62 Channel 2 Output
	U2C0_DX0E	I	St/B	USIC2 Channel 0 Shift Data Input
	CCU60_CCP OS2B	I	St/B	CCU60 Position Input 2
128	P10.14	O0 / I	St/B	Bit 14 of Port 10, General Purpose Input/Output
	U1C0_SELO 1	O1	St/B	USIC1 Channel 0 Select/Control 1 Output
	U0C1_DOUT	O2	St/B	USIC0 Channel 1 Shift Data Output
	U3C0_SCLK OUT	O3	St/B	USIC3 Channel 0 Shift Clock Output
	$\overline{\text{RD}}$	OH	St/B	External Bus Interface Read Strobe Output
	ESR2_2	I	St/B	ESR2 Trigger Input 2
	U0C1_DX0C	I	St/B	USIC0 Channel 1 Shift Data Input
	RxDC3C	I	St/B	CAN Node 3 Receive Data Input
	U3C0_DX1A	I	St/B	USIC3 Channel 0 Shift Clock Input
129	P1.4	O0 / I	St/B	Bit 4 of Port 1, General Purpose Input/Output
	CCU62_COU T61	O1	St/B	CCU62 Channel 1 Output
	U1C1_SELO 4	O2	St/B	USIC1 Channel 1 Select/Control 4 Output
	U2C0_SELO 5	O3	St/B	USIC2 Channel 0 Select/Control 5 Output
	A12	OH	St/B	External Bus Interface Address Line 12
	U2C0_DX2B	I	St/B	USIC2 Channel 0 Shift Control Input
	RxDC5A	I	St/B	CAN Node 5 Receive Data Input

Functional Description

8 Kbytes of on-chip Stand-By SRAM (SBRAM) provide storage for system-relevant user data that must be preserved while the major part of the device is powered down. The SBRAM is accessed via a specific interface and is powered in domain M.

1024 bytes (2 × 512 bytes) of the address space are reserved for the Special Function Register areas (SFR space and ESFR space). SFRs are word-wide registers which are used to control and monitor functions of the different on-chip units. Unused SFR addresses are reserved for future members of the XC2000 Family. In order to ensure upward compatibility they should either not be accessed or written with zeros.

The on-chip Flash memory stores code, constant data, and control data. The on-chip Flash memory consists of 1 module of 64 Kbytes (preferably for data storage) and modules with a maximum capacity of 256 Kbytes each. Each module is organized in sectors of 4 Kbytes.

The uppermost 4-Kbyte sector of segment 0 (located in Flash module 0) is used internally to store operation control parameters and protection information.

Note: The actual size of the Flash memory depends on the chosen device type.

Each sector can be separately write protected¹⁾, erased and programmed (in blocks of 128 Bytes). The complete Flash area can be read-protected. A user-defined password sequence temporarily unlocks protected areas. The Flash modules combine 128-bit read access with protected and efficient writing algorithms for programming and erasing. Dynamic error correction provides extremely high read data security for all read access operations. Access to different Flash modules can be executed in parallel. For Flash parameters, please see [Section 4.5](#).

Memory Content Protection

The contents of on-chip memories can be protected against soft errors (induced e.g. by radiation) by activating the parity mechanism or the Error Correction Code (ECC).

The parity mechanism can detect a single-bit error and prevent the software from using incorrect data or executing incorrect instructions.

The ECC mechanism can detect and automatically correct single-bit errors. This supports the stable operation of the system.

It is strongly recommended to activate the ECC mechanism wherever possible because this dramatically increases the robustness of an application against such soft errors.

1) To save control bits, sectors are clustered for protection purposes, they remain separate for programming/erasing.

3.2 External Bus Controller

All external memory access operations are performed by a special on-chip External Bus Controller (EBC). The EBC also controls access to resources connected to the on-chip LxBus (MultiCAN and the USIC modules). The LxBus is an internal representation of the external bus that allows access to integrated peripherals and modules in the same way as to external components.

The EBC can be programmed either to Single Chip Mode, when no external memory is required, or to an external bus mode with the following selections¹⁾:

- Address Bus Width with a range of 0 ... 24-bit
- Data Bus Width 8-bit or 16-bit
- Bus Operation Multiplexed or Demultiplexed

The bus interface uses Port 10 and Port 2 for addresses and data. In the demultiplexed bus modes, the lower addresses are output separately on Port 0 and Port 1. The number of active segment address lines is selectable, restricting the external address space to 8 Mbytes ... 64 Kbytes. This is required when interface lines shall be assigned to Port 2.

External $\overline{\text{CS}}$ signals (address windows plus default) can be generated and output on Port 4 in order to save external glue logic. External modules can be directly connected to the common address/data bus and their individual select lines.

A $\overline{\text{HOLD}}/\text{HLDA}$ protocol is available for bus arbitration; this allows the sharing of external resources with other bus masters. The bus arbitration is enabled by software, after which pins P3.0 ... P3.2 ($\overline{\text{BREQ}}$, $\overline{\text{HLDA}}$, $\overline{\text{HOLD}}$) are automatically controlled by the EBC. In Master Mode (default after reset) the $\overline{\text{HLDA}}$ pin is an output. In Slave Mode pin $\overline{\text{HLDA}}$ is switched to be an input. This allows the direct connection of the slave controller to another master controller without glue logic.

Important timing characteristics of the external bus interface are programmable (with registers TCONCSx/FCONCSx) to allow the user to adapt it to a wide range of different types of memories and external peripherals.

Access to very slow memories or modules with varying access times is supported by a special 'Ready' function. The active level of the control input signal is selectable.

In addition, up to four independent address windows may be defined (using registers ADDRSELx) to control access to resources with different bus characteristics. These address windows are arranged hierarchically where window 4 overrides window 3, and window 2 overrides window 1. All accesses to locations not covered by these four address windows are controlled by TCONCS0/FCONCS0. The currently active window can generate a chip select signal.

The external bus timing is based on the rising edge of the reference clock output CLKOUT. The external bus protocol is compatible with that of the standard C166 Family.

¹⁾ Bus modes are switched dynamically if several address windows with different mode settings are used.

3.6 Interrupt System

The architecture of the XC228xM supports several mechanisms for fast and flexible response to service requests; these can be generated from various sources internal or external to the microcontroller. Any of these interrupt requests can be programmed to be serviced by the Interrupt Controller or by the Peripheral Event Controller (PEC).

Where in a standard interrupt service the current program execution is suspended and a branch to the interrupt vector table is performed, just one cycle is 'stolen' from the current CPU activity to perform a PEC service. A PEC service implies a single byte or word data transfer between any two memory locations with an additional increment of either the PEC source pointer, the destination pointer, or both. An individual PEC transfer counter is implicitly decremented for each PEC service except when performing in the continuous transfer mode. When this counter reaches zero, a standard interrupt is performed to the corresponding source-related vector location. PEC services are particularly well suited to supporting the transmission or reception of blocks of data. The XC228xM has eight PEC channels, each with fast interrupt-driven data transfer capabilities.

With a minimum interrupt response time of $7/11^{1)}$ CPU clocks, the XC228xM can react quickly to the occurrence of non-deterministic events.

Interrupt Nodes and Source Selection

The interrupt system provides 96 physical nodes with separate control register containing an interrupt request flag, an interrupt enable flag and an interrupt priority bit field. Most interrupt sources are assigned to a dedicated node. A particular subset of interrupt sources shares a set of nodes. The source selection can be programmed using the interrupt source selection (ISSR) registers.

External Request Unit (ERU)

A dedicated External Request Unit (ERU) is provided to route and preprocess selected on-chip peripheral and external interrupt requests. The ERU features 4 programmable input channels with event trigger logic (ETL) a routing matrix and 4 output gating units (OGU). The ETL features rising edge, falling edge, or both edges event detection. The OGU combines the detected interrupt events and provides filtering capabilities depending on a programmable pattern match or miss.

Trap Processing

The XC228xM provides efficient mechanisms to identify and process exceptions or error conditions that arise during run-time, the so-called 'Hardware Traps'. A hardware trap causes an immediate system reaction similar to a standard interrupt service (branching

¹⁾ Depending if the jump cache is used or not.

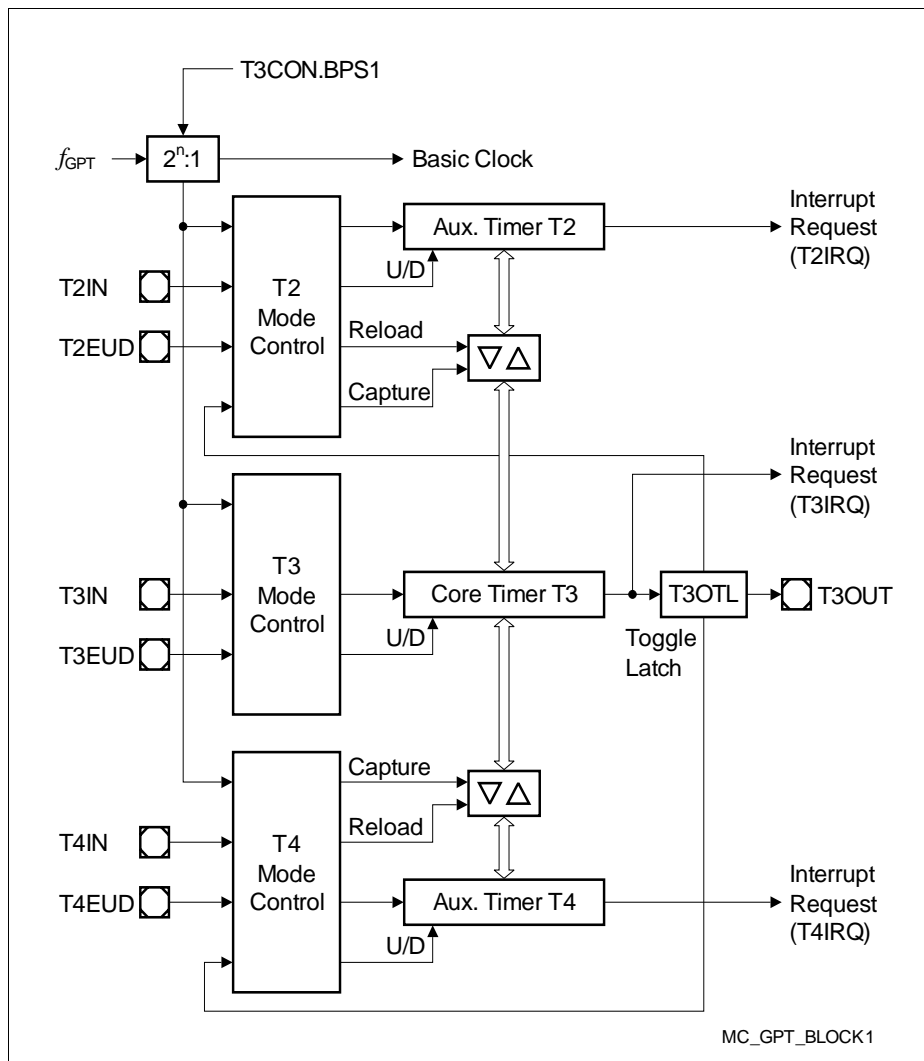


Figure 8 Block Diagram of GPT1

3.11 Real Time Clock

The Real Time Clock (RTC) module of the XC228xM can be clocked with a clock signal selected from internal sources or external sources (pins).

The RTC basically consists of a chain of divider blocks:

- Selectable 32:1 and 8:1 dividers (on - off)
- The reloadable 16-bit timer T14
- The 32-bit RTC timer block (accessible via registers RTCH and RTCL) consisting of:
 - a reloadable 10-bit timer
 - a reloadable 6-bit timer
 - a reloadable 6-bit timer
 - a reloadable 10-bit timer

All timers count up. Each timer can generate an interrupt request. All requests are combined to a common node request.

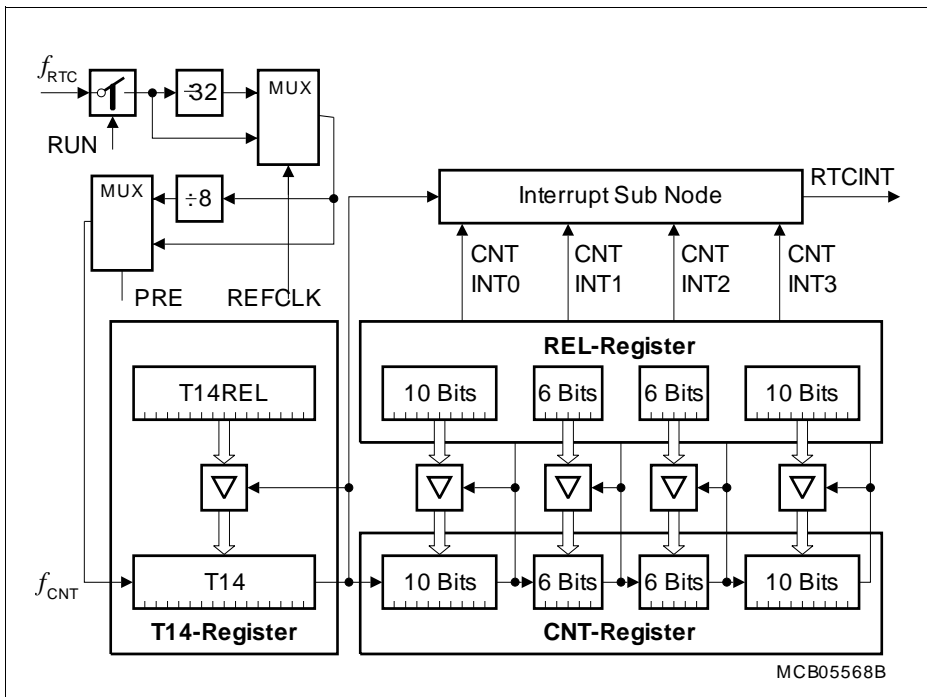


Figure 10 RTC Block Diagram

Note: The registers associated with the RTC are only affected by a power reset.

Functional Description

Table 11 Instruction Set Summary (cont'd)

Mnemonic	Description	Bytes
ROL/ROR	Rotate left/right direct word GPR	2
ASHR	Arithmetic (sign bit) shift right direct word GPR	2
MOV(B)	Move word (byte) data	2 / 4
MOVBS/Z	Move byte operand to word op. with sign/zero extension	2 / 4
JMPA/I/R	Jump absolute/indirect/relative if condition is met	4
JMPS	Jump absolute to a code segment	4
JB(C)	Jump relative if direct bit is set (and clear bit)	4
JNB(S)	Jump relative if direct bit is not set (and set bit)	4
CALLA/I/R	Call absolute/indirect/relative subroutine if condition is met	4
CALLS	Call absolute subroutine in any code segment	4
PCALL	Push direct word register onto system stack and call absolute subroutine	4
TRAP	Call interrupt service routine via immediate trap number	2
PUSH/POP	Push/pop direct word register onto/from system stack	2
SCXT	Push direct word register onto system stack and update register with word operand	4
RET(P)	Return from intra-segment subroutine (and pop direct word register from system stack)	2
RETS	Return from inter-segment subroutine	2
RETI	Return from interrupt service subroutine	2
SBRK	Software Break	2
SRST	Software Reset	4
IDLE	Enter Idle Mode	4
PWRDN	Unused instruction ¹⁾	4
SRVWDT	Service Watchdog Timer	4
DISWDT/ENWDT	Disable/Enable Watchdog Timer	4
EINIT	End-of-Initialization Register Lock	4
ATOMIC	Begin ATOMIC sequence	2
EXTR	Begin EXTENDED Register sequence	2
EXTP(R)	Begin EXTENDED Page (and Register) sequence	2 / 4
EXTS(R)	Begin EXTENDED Segment (and Register) sequence	2 / 4

Functional Description

Table 11 Instruction Set Summary (cont'd)

Mnemonic	Description	Bytes
NOP	Null operation	2
CoMUL/CoMAC	Multiply (and accumulate)	4
CoADD/CoSUB	Add/Subtract	4
Co(A)SHR	(Arithmetic) Shift right	4
CoSHL	Shift left	4
CoLOAD/STORE	Load accumulator/Store MAC register	4
CoCMP	Compare	4
CoMAX/MIN	Maximum/Minimum	4
CoABS/CoRND	Absolute value/Round accumulator	4
CoMOV	Data move	4
CoNEG/NOP	Negate accumulator/Null operation	4

- 1) The Enter Power Down Mode instruction is not used in the XC228xM, due to the enhanced power control scheme. PWRDN will be correctly decoded, but will trigger no action.

4.3 Analog/Digital Converter Parameters

These parameters describe the conditions for optimum ADC performance.

Note: Operating Conditions apply.

Table 18 ADC Parameters

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Switched capacitance at an analog input	C_{AINSW} CC	–	4	5	pF	not subject to production test ¹⁾
Total capacitance at an analog input	C_{AINT} CC	–	10	12	pF	not subject to production test ¹⁾
Switched capacitance at the reference input	C_{AREFSW} CC	–	7	9	pF	not subject to production test ¹⁾
Total capacitance at the reference input	C_{AREFT} CC	–	13	15	pF	not subject to production test ¹⁾
Differential Non-Linearity Error	$ EA_{DNL} $ CC	–	0.8	1.0	LSB	not subject to production test
Gain Error	$ EA_{GAIN} $ CC	–	0.4	0.8	LSB	not subject to production test
Integral Non-Linearity	$ EA_{INL} $ CC	–	0.8	1.2	LSB	not subject to production test
Offset Error	$ EA_{OFF} $ CC	–	0.5	0.8	LSB	not subject to production test
Analog clock frequency	f_{ADCI} SR	0.5	–	20	MHz	Upper voltage range
		0.5	–	16.5	MHz	Lower voltage range
Input resistance of the selected analog channel	R_{AIN} CC	–	–	2	kOhm	not subject to production test ¹⁾
Input resistance of the reference input	R_{AREF} CC	–	–	2	kOhm	not subject to production test ¹⁾

4.5 Flash Memory Parameters

The XC228xM is delivered with all Flash sectors erased and with no protection installed. The data retention time of the XC228xM's Flash memory (i.e. the time after which stored data can still be retrieved) depends on the number of times the Flash memory has been erased and programmed.

Note: These parameters are not subject to production test but verified by design and/or characterization.

Note: Operating Conditions apply.

Table 23 Flash Parameters

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Parallel Flash module program/erase limit depending on Flash read activity	N_{PP} SR	—	—	4 ¹⁾		$N_{FL_RD} \leq 1$, $f_{SYS} \leq 80$ MHz
		—	—	1 ²⁾		$N_{FL_RD} > 1$
Flash erase endurance for security pages	N_{SEC} SR	10	—	—	cycles	$t_{RET} \geq 20$ years
Flash wait states ³⁾	N_{WSFLAS} H SR	1	—	—		$f_{SYS} \leq 8$ MHz
		2	—	—		$f_{SYS} \leq 13$ MHz
		3	—	—		$f_{SYS} \leq 17$ MHz
		4	—	—		$f_{SYS} > 17$ MHz
Erase time per sector/page	t_{ER} CC	—	7 ⁴⁾	8.0	ms	
Programming time per page	t_{PR} CC	—	3 ⁴⁾	3.5	ms	
Data retention time	t_{RET} CC	20	—	—	years	$N_{Er} \leq 1\,000$ cycles
Drain disturb limit	N_{DD} SR	32	—	—	cycles	

Electrical Parameters

Table 27 is valid under the following conditions:

$V_{DDP} \geq 3.0 \text{ V}$; $V_{DDPtyp} = 3.3 \text{ V}$; $V_{DDP} \leq 4.5 \text{ V}$; $C_L \geq 20 \text{ pF}$; $C_L \leq 100 \text{ pF}$;

Table 27 Standard Pad Parameters for Lower Voltage Range

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Maximum output driver current (absolute value) ¹⁾	I_{Omax} CC	—	—	10	mA	Strong driver
		—	—	2.5	mA	Medium driver
		—	—	0.5	mA	Weak driver
Nominal output driver current (absolute value)	I_{Onom} CC	—	—	2.5	mA	Strong driver
		—	—	1.0	mA	Medium driver
		—	—	0.1	mA	Weak driver
Rise and Fall times (10% - 90%)	t_{RF} CC	—	—	$6.2 + 0.24 \times C_L$	ns	Strong driver; Sharp edge
		—	—	$24 + 0.3 \times C_L$	ns	Strong driver; Medium edge
		—	—	$34 + 0.3 \times C_L$	ns	Strong driver; Slow edge
		—	—	$37 + 0.65 \times C_L$	ns	Medium driver
		—	—	$500 + 2.5 \times C_L$	ns	Weak driver

1) The total output current that may be drawn at a given time must be limited to protect the supply rails from damage. For any group of 16 neighboring output pins, the total output current in each direction (ΣI_{OL} and ΣI_{OH}) must remain below 50 mA.

4.6.5.1 Bus Cycle Control with the READY Input

The duration of an external bus cycle can be controlled by the external circuit using the READY input signal. The polarity of this input signal can be selected.

Synchronous READY permits the shortest possible bus cycle but requires the input signal to be synchronous to the reference signal CLKOUT.

An asynchronous READY signal puts no timing constraints on the input signal but incurs a minimum of one waitstate due to the additional synchronization stage. The minimum duration of an asynchronous READY signal for safe synchronization is one CLKOUT period plus the input setup time.

An active READY signal can be deactivated in response to the trailing (rising) edge of the corresponding command (\overline{RD} or \overline{WR}).

If the next bus cycle is controlled by READY, an active READY signal must be disabled before the first valid sample point in the next bus cycle. This sample point depends on the programmed phases of the next cycle.

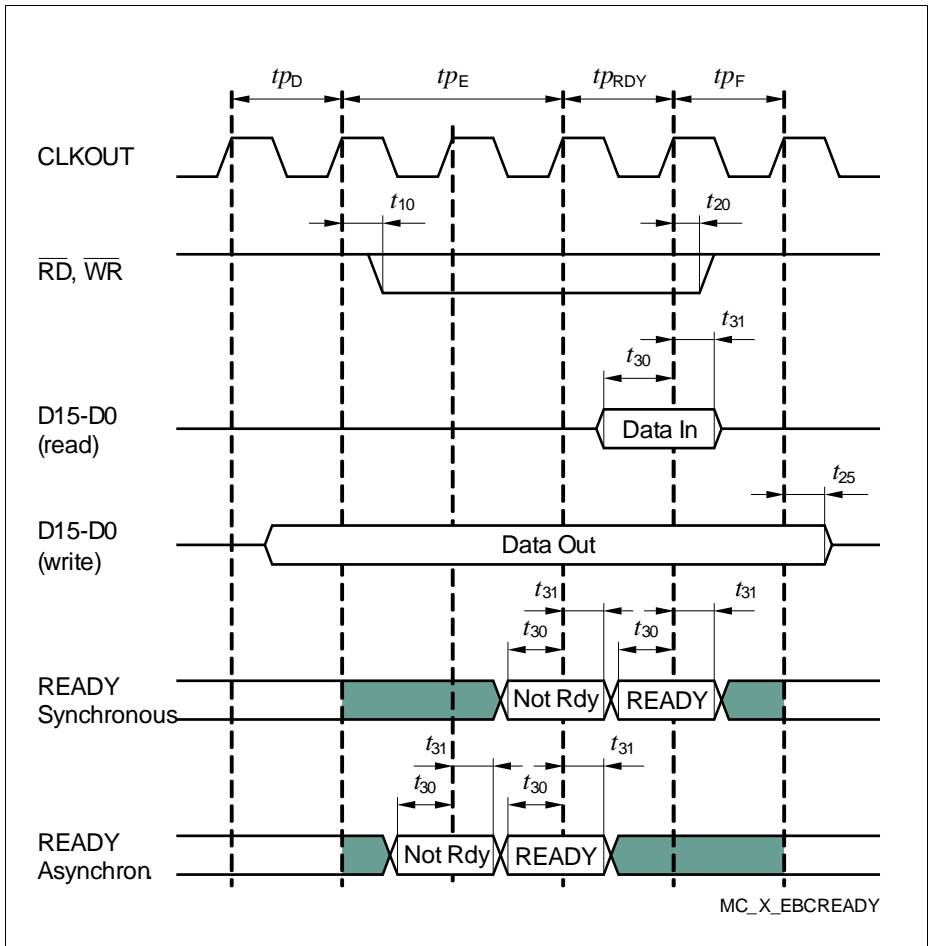


Figure 25 **READY Timing**

Note: If the READY input is sampled inactive at the indicated sampling point ("Not Rdy") a READY-controlled waitstate is inserted (tp_{RDY}), sampling the READY input active at the indicated sampling point ("Ready") terminates the currently running bus cycle.

Note the different sampling points for synchronous and asynchronous READY. This example uses one mandatory waitstate (see tp_E) before the READY input value is used.

4.6.5.2 External Bus Arbitration

If the arbitration signals are enabled, the XC228xM makes its external resources available in response to an arbitration request.

Note: Operating Conditions apply.

Table 32 Bus Arbitration Timing for Upper Voltage Range

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Input setup time HOLD input	t_{40} SR	23		–	ns	
Output delay rising edge HLDA, BREQ	t_{41} CC	-1		13	ns	
Output delay falling edge HLDA	t_{42} CC	-2		14	ns	

Table 33 Bus Arbitration Timing for Lower Voltage Range

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Input setup time HOLD input	t_{40} SR	28		–	ns	
Output delay rising edge HLDA, BREQ	t_{41} CC	-1		19	ns	
Output delay falling edge HLDA	t_{42} CC	-2		21	ns	

Table 41 JTAG Interface Timing for Lower Voltage Range

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
TCK clock period	t_1 SR	50 ¹⁾	—	—	ns	2)
TCK high time	t_2 SR	16	—	—	ns	
TCK low time	t_3 SR	16	—	—	ns	
TCK clock rise time	t_4 SR	—	—	8	ns	
TCK clock fall time	t_5 SR	—	—	8	ns	
TDI/TMS setup to TCK rising edge	t_6 SR	6	—	—	ns	
TDI/TMS hold after TCK rising edge	t_7 SR	6	—	—	ns	
TDO valid from TCK falling edge (propagation delay) ³⁾	t_8 CC	—	32	36	ns	
TDO high impedance to valid output from TCK falling edge ⁴⁾³⁾	t_9 CC	—	32	36	ns	
TDO valid output to high impedance from TCK falling edge ³⁾	t_{10} CC	—	32	36	ns	
TDO hold after TCK falling edge ³⁾	t_{18} CC	5	—	—	ns	

1) The debug interface cannot operate faster than the overall system, therefore $t_1 \geq t_{SYS}$.

2) Under typical conditions, the interface can operate at transfer rates up to 20 MHz.

3) The falling edge on TCK is used to generate the TDO timing.

4) The setup time for TDO is given implicitly by the TCK cycle time.